



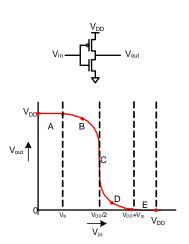
CMOS Inverter Additional Slides

Vishal Saxena ECE, Boise State University

Oct 21, 2010



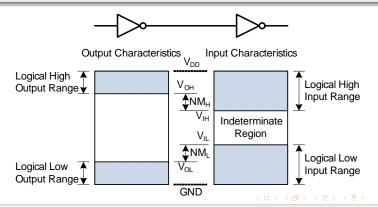
Region	NMOS	PMOS
A	Cutoff	Triode
В	Saturation	Triode
С	Saturation	Saturation
D	Triode	Saturation
Е	Triode	Cutoff



Noise Margin



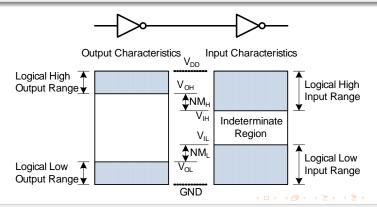
- How much noise can a gate input see before it does not recognize the output?
 - Noise margins of a digital gate indicate how well it will perform with noisy input



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 - Noise margins of a digital gate indicate how well it will perform with noisy input







- $NM_H = V_{IH} V_{OH}$
 - HIGH noise margin
- $NM_I = V_{II} V_{OI}$
 - LOW noise margin
- $V_{IH} = \text{minimum HIGH input voltage}$
- $V_{II} = \text{maximum LOW input voltage}$
- $V_{OH} = \text{minimum HIGH output voltage}$
- $V_{OI} = \text{maximum LOW}$ output voltage





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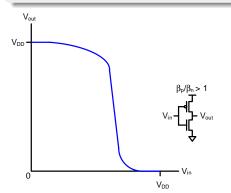


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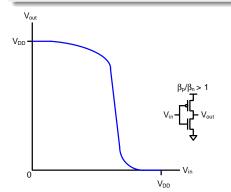
- To maximize noise margins, select logic levels at
 - unity gain point of DC transfer characteristics







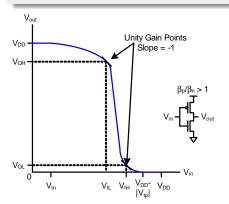
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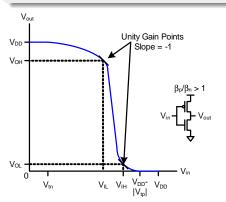
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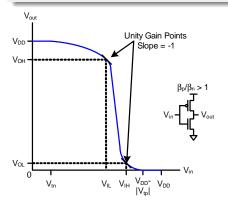
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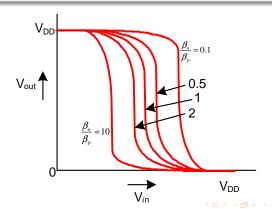
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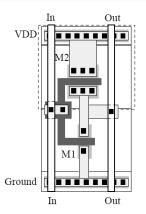
- If $\frac{\beta_n}{\beta_p} \neq 1$, inverter's switching point (V_{SP}) will move from the ideal value of $\frac{V_{DD}}{2}$
 - called skewed gate

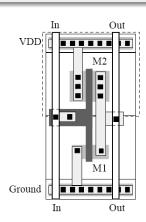


Inverter Layout



- Two styles for laying out an inverter
- Power and ground routed on metal-1 using standard frame

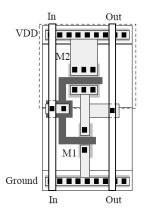


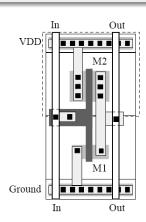


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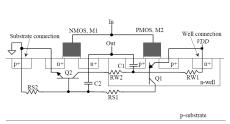




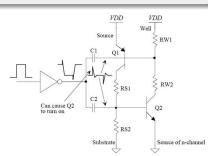
Latch-up



- Fast voltage pulses can feed-through the C1 or C2 and turn on the parasitic BJT
- If any of the BJT is turned on, it creates a positive feedback loop



Cross-sectional view of an inverter showing parasitic bipolar transistors and resistors



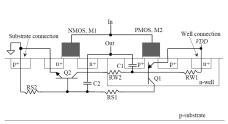
Schematic for understanding latch-up



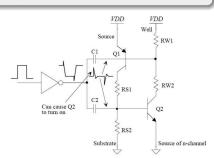
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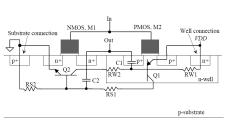
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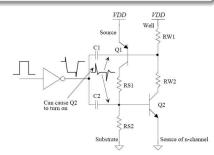
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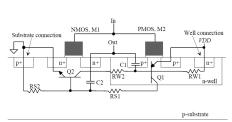


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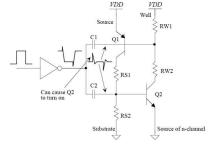
Latch-up prevention



- Reduce the well series resistances (RW1 and RW2) by using as many contacts as possible and closer to the inverter
 - can also use guard ring structures
- Use slow rise and fall times in the logic
- Reduce drain areas to reduce C1 and C2



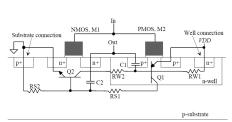
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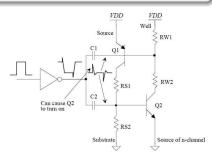
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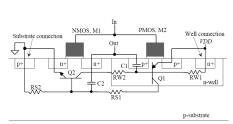


Schematic for understanding latch-up \Box

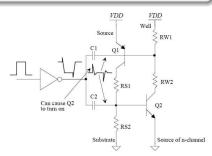
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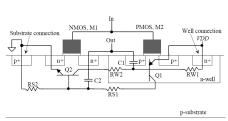


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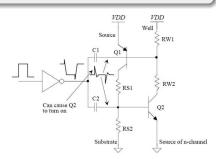




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- In nm-CMOS, assuming that for equal drive strengths $W_p = 2W_n$
 - effective switching resistance of PMOS & NMOS = R
 - in MOSFETs switching model assume that $C_{in} = C_{out} = C$
- Propgataion delay $(d) = t_{pLH} = t_{pHL} = 0.7 \times R(C_{outp} + C_{outn}) \triangleq 0.7 \times 3RC$
- Can express delay in a process-independent unit
 - $d = d_{abs}/0.7\tau$
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Delay in a Logic Gate



■ Can express delay in a process-independent unit

 \blacksquare Delay has two components: d = f + p

■ h: electrical effort=
$$C_{out}/C_{int}$$





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again has two components:

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measures relative ability of gate to deliver currentg=1 for inverter (baseline circuit)

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ratio of output to input capacitancesometimes called fanout

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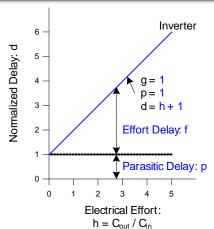
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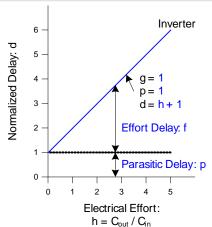
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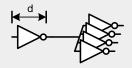
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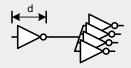
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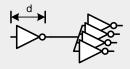
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- Parasitic Delay: p = 1
- Stage Delay: d = 5
- The FO4 delay is about 300 ps in 0.5 µm process 15 ps in a 65 nm process





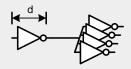
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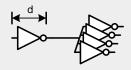
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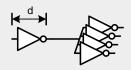
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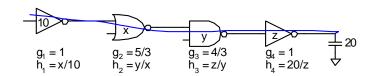


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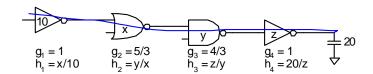
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- Path Logical Effort $G = \prod g_i$
- Path Electrical Effort $H = \frac{C_{out-path}}{C_{in-path}}$
- Path Effort $F = \prod f_i = \prod g_i h_i$
- For a single path (no branching): $F = G \cdot H$







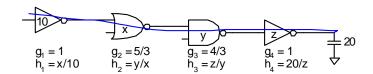
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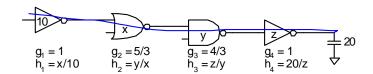
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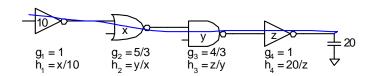
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Multistage Delays



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- Path Parasitic Delay $P = \sum p_i$
- Path Delay $D = \sum d_i = D_F + P$



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- $D = \sum d_i = D_F + P$
- Delay is smallest when each stage bears same effort

$$\hat{f} = g_i h_i = F^{\frac{1}{N}}$$

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Designing Fast Circuits



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■ How wide should the gates be for least delay?

$$\hat{f} = gh = g \frac{C_{out}}{C}$$

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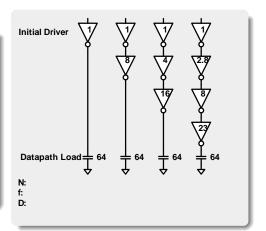


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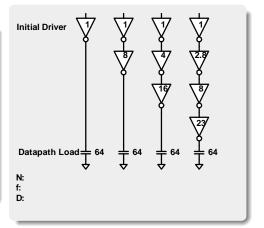
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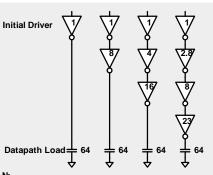




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N:

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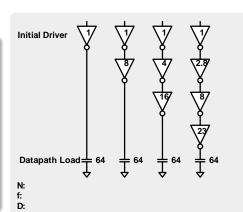




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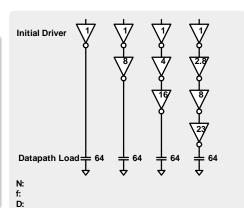




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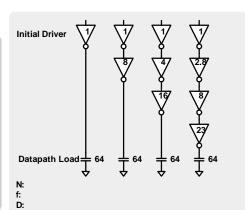




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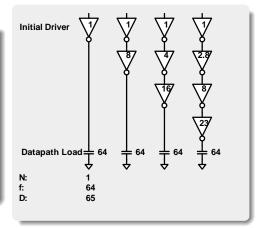




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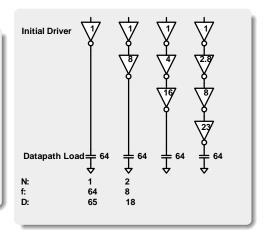




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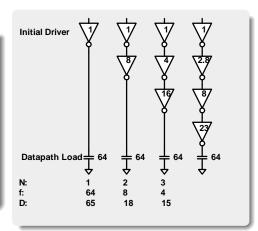




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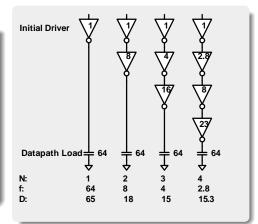




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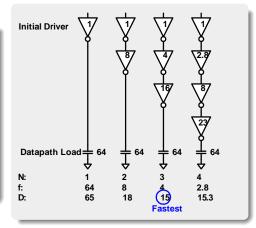




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- How many inverters in a buffer give the least delay?
- For N inverters: $D = NF^{\frac{1}{N}} + N \cdot p_{inv}$

p_{inv} is the parasitic delay of the inverter, F is the path efform
 Path Effort: F = G · H = Cot

- Minimize delay: $\frac{\partial D}{\partial N} = -F^{\frac{1}{N}} \cdot ln\left(F^{\frac{1}{N}}\right) + F^{\frac{1}{N}} + p_{inv} = 0$
- Define best stage effort $\rho = F^{\frac{1}{N}}$

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Best Stage Effort



- $p_{inv} + \rho(1 ln\rho) = 0$ has no closed form solution
- Neglecting parasitics ($p_{inv} = 0$) we find $\rho = e = 2.718$
- For $p_{inv} = 1$, numerical solution yields $\rho = 3.59$
- Least delay for:
 - stage effort (or fan-out) equal to $\rho = F^{\frac{1}{N}} = 4$ ■ and when using $\hat{N} = log_{\rho}F$
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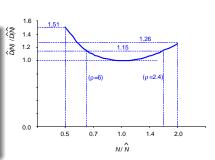


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- $2.4 < \rho < 6$ gives delay within 15% of optimal

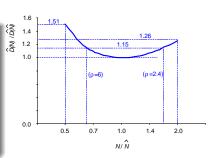




Sensitivity Analysis



- How sensitive is delay to using exactly the best number of stages?
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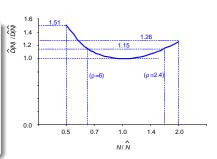




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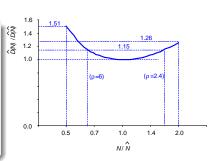




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Method of Logical Effort



■ Note that for the buffer design problem: G = B = 1, $g_i = 1$, and $F = H = \frac{C_{out}}{C_{in}}$



Minimizing Layout Area?



- Total transistor area can be roughly estimated as $A = A_1 \sum_{i=0}^{N-1} (\hat{f})^N$, where A_1 is the area of the first inverter.
- The area can be minimized for a specified delay (D_0) by optimizing the following set of constraints

minimize
$$\frac{\left(\hat{f}\right)^{N}-1}{\hat{f}-1}$$

for
$$D = P + N\hat{f} \le D_0$$

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References I





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